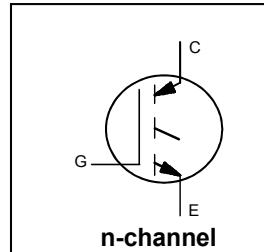


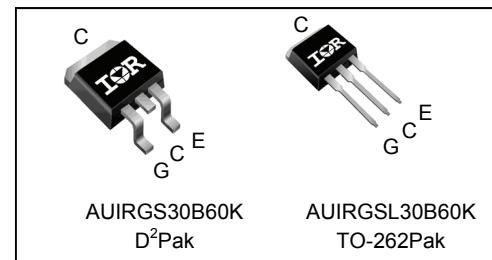
INSULATED GATE BIPOLEAR TRANSISTOR

Features

- Low $V_{CE(on)}$ Non Punch Through IGBT Technology
- 10 μ s Short Circuit Capability
- Square RBSOA
- Positive $V_{CE(on)}$ Temperature Coefficient.
- Maximum Junction Temperature rated at 175°C
- Lead-Free, RoHS Compliant
- Automotive Qualified * *



$V_{CES} = 600V$
 $I_C = 50A, T_C = 100C$
At $T_J = 175^\circ C$
 $t_{SC} \geq 10\mu s, T_J = 150^\circ C$
 $V_{CE(on)} \text{ typ.} = 1.95V$



G	C	E
Gate	Collector	Emitter

Base Part Number	Package Type	Standard Pack		Orderable Part Number	
		Form	Quantity		
AUIRGSL30B60K	TO-262	Tube	50	AUIRGSL30B60K	
AUIRG30B60K		Tube	50	AUIRG30B60K	
		Tape and Reel Left	800	AUIRG30B60KTRL	
		Tape and Reel Right	800	AUIRG30B60KTRR	

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (T_A) is 25°C, unless otherwise specified.

	Parameter	Max.	Units
V_{CES}	Collector-to-Emitter Voltage	600	V
$I_C @ T_C = 25^\circ C$	Continuous Collector Current	78	A
$I_C @ T_C = 100^\circ C$	Continuous Collector Current	50	
I_{CM}	Pulse Collector Current (Ref.Fig.C.T.5)	120	
I_{LM}	Clamped Inductive Load Current ①	120	
V_{ISOL}	RMS Isolation Voltage, Terminal to Case, t=1 min.	2500	V
V_{GE}	Continuous Gate-to-Emitter Voltage	± 20	
$P_D @ T_C = 25^\circ C$	Maximum Power Dissipation	370	W
$P_D @ T_C = 100^\circ C$	Maximum Power Dissipation	180	
T_J	Operating Junction and	-55 to +175	$^\circ C$
T_{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 sec.	300 (0.063 in.(1.6mm) from case)	

Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$ (IGBT)	Thermal Resistance Junction-to-Case (IGBT)	—	—	0.41*	$^\circ C/W$
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink (flat, greased surface)	—	0.50	—	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (typical socket mount)	—	—	40	
Wt	Weight	—	1.44	—	

* $R_{\theta JC}$ (end of life) = 0.65°C/W. This is the maximum measured value after 1000 temperature cycles from -55 to 150°C and is accounted for by the physical wearout of the die attach medium.

** Qualification standards can be found at www.infineon.com

Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions	Ref. Fig.
$V_{(\text{BR})\text{CES}}$	Collector-to-Emitter Breakdown Voltage	600	—	—	V	$V_{\text{GE}} = 0\text{V}$, $I_C = 500\mu\text{A}$	
$\Delta V_{(\text{BR})\text{CES}/\Delta T_J}$	Temperature Coeff. of Breakdown Voltage	—	0.40	—	V/ $^\circ\text{C}$	$V_{\text{GE}} = 0\text{V}$, $I_C = 1\text{mA}$ (25°C - 150°C)	
$V_{\text{CE}(\text{on})}$	Collector-to-Emitter Saturation Voltage	—	1.95	2.35	V	$I_C = 30\text{A}$, $V_{\text{GE}} = 15\text{V}$, $T_J = 25^\circ\text{C}$	5,6,7
		—	2.40	2.75		$I_C = 30\text{A}$, $V_{\text{GE}} = 15\text{V}$, $T_J = 150^\circ\text{C}$	8,9,10
		—	2.6	2.95		$I_C = 30\text{A}$, $V_{\text{GE}} = 15\text{V}$, $T_J = 175^\circ\text{C}$	
$V_{\text{GE}(\text{th})}$	Gate Threshold Voltage	3.5	4.5	5.5	V	$I_C = 250\mu\text{A}$	8,9,10,
$\Delta V_{\text{GE}(\text{th})/\Delta T_J}$	Threshold Voltage temp. coefficient	—	-10	—	mV/ $^\circ\text{C}$	$V_{\text{CE}} = V_{\text{GE}}$, $I_C = 1.0\text{mA}$ (25°C - 150°C)	11
g_{fe}	Forward Transconductance	—	18	—	S	$V_{\text{CE}} = 50\text{V}$, $I_C = 50\text{A}$, $PW = 80\mu\text{s}$	
I_{CES}	Collector-to-Emitter Leakage Current	—	5.0	250	μA	$V_{\text{GE}} = 0\text{V}$, $V_{\text{CE}} = 600\text{V}$	
		—	1000	2000		$V_{\text{GE}} = 0\text{V}$, $V_{\text{CE}} = 600\text{V}$, $T_J = 150^\circ\text{C}$	
		—	1830	3000		$V_{\text{GE}} = 0\text{V}$, $V_{\text{CE}} = 600\text{V}$, $T_J = 175^\circ\text{C}$	
I_{GES}	Gate-to-Emitter Leakage Current	—	—	± 100	nA	$V_{\text{GE}} = \pm 20\text{V}$, $V_{\text{CE}} = 0\text{V}$	

Switching Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions	Ref. Fig.
Q_g	Total Gate Charge (turn-on)	—	102	153	nC	$I_C = 30\text{A}$ $V_{\text{GE}} = 15\text{V}$ $V_{\text{CC}} = 400\text{V}$	17 CT1
Q_{ge}	Gate-to-Emitter Charge (turn-on)	—	14	21			
Q_{gc}	Gate-to-Collector Charge (turn-on)	—	44	66			
E_{on}	Turn-On Switching Loss	—	350	620	μJ	$I_C = 30\text{A}$, $V_{\text{CC}} = 400\text{V}$, $V_{\text{GE}} = +15\text{V}$, $R_G = 10\Omega$, $L = 200\mu\text{H}$, $T_J = 25^\circ\text{C}$ ③	CT4
E_{off}	Turn-Off Switching Loss	—	825	955			
E_{total}	Total Switching Loss	—	1175	1575			
$t_{\text{d(on)}}$	Turn-On delay time	—	46	60	ns		CT4
t_r	Rise time	—	28	39			
$t_{\text{d(off)}}$	Turn-Off delay time	—	185	200			
t_f	Fall time	—	31	40	μJ	$I_C = 30\text{A}$, $V_{\text{CC}} = 400\text{V}$, $V_{\text{GE}} = +15\text{V}$, $R_G = 10\Omega$, $L = 200\mu\text{H}$, $T_J = 150^\circ\text{C}$	WF1,WF2
E_{on}	Turn-On Switching Loss	—	635	1085			
E_{off}	Turn-Off Switching Loss	—	1150	1350			
E_{total}	Total Switching Loss	—	1785	2435	ns		
$t_{\text{d(on)}}$	Turn-On delay time	—	46	60		WF1,WF2	
t_r	Rise time	—	28	39			
$t_{\text{d(off)}}$	Turn-Off delay time	—	205	235			
t_f	Fall time	—	32	42	$n\text{H}$	Measured 5mm from package	WF2
L_E	Internal Emitter Inductance	—	7.5	—			
C_{ies}	Input Capacitance	—	1750	—	pF		
C_{oes}	Output Capacitance	—	160	—	$V_{\text{GE}} = 0\text{V}$ $V_{\text{CC}} = 30\text{V}$ $f = 1.0\text{Mhz}$	16	
C_{res}	Reverse Transfer Capacitance	—	60	—			
RBSOA	Reverse Bias Safe Operating Area	FULL SQUARE				$T_J = 150^\circ\text{C}$, $I_C = 120\text{A}$, $V_p = 600\text{V}$ $V_{\text{CC}} = 500\text{V}$, $V_{\text{GE}} = +15\text{V}$ to 0V $R_g = 10\Omega$	4 CT2
SCSOA	Short Circuit Safe Operating Area	10	—	—	μs	$T_J = 150^\circ\text{C}$, $V_p = 600\text{V}$, $R_g = 10\Omega$ $V_{\text{CC}} = 360\text{V}$, $V_{\text{GE}} = +15\text{V}$ to 0V	CT3 WF3
$I_{\text{sc}}(\text{Peak})$	Peak Short Circuit Collector Current	—	200	—	A		WF3

Notes:

- ① $V_{\text{CC}} = 80\%$ (V_{CES}), $V_{\text{GE}} = 20\text{V}$, $L = 28\mu\text{H}$, $R_G = 22\Omega$.
- ② This is applied to D2Pak, when mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- ③ Energy losses include "tail" and diode reverse recovery.

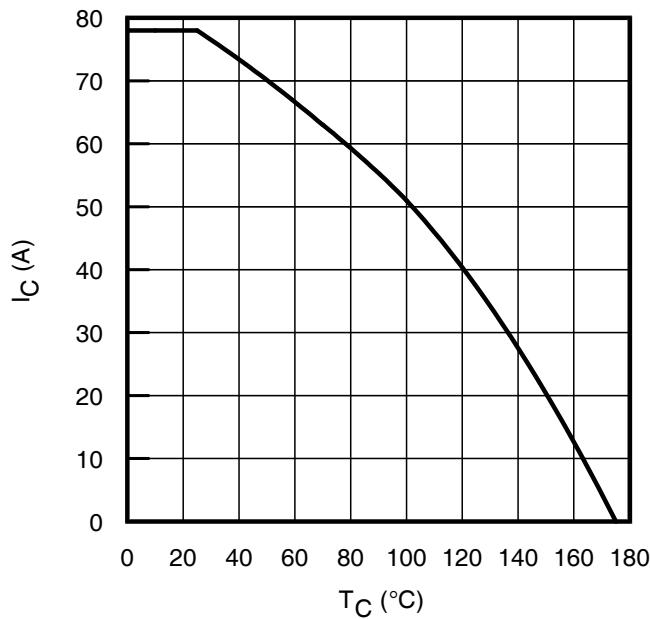


Fig. 1 - Maximum DC Collector Current vs.
Case Temperature

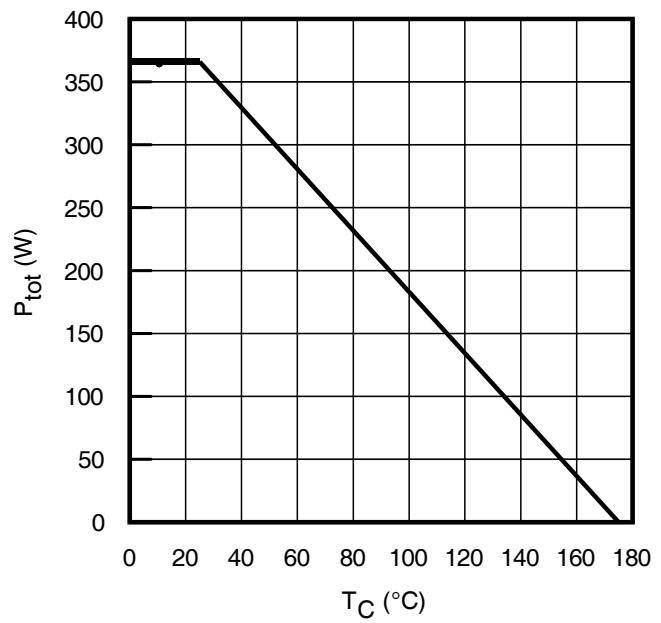


Fig. 2 - Power Dissipation vs.
Case Temperature

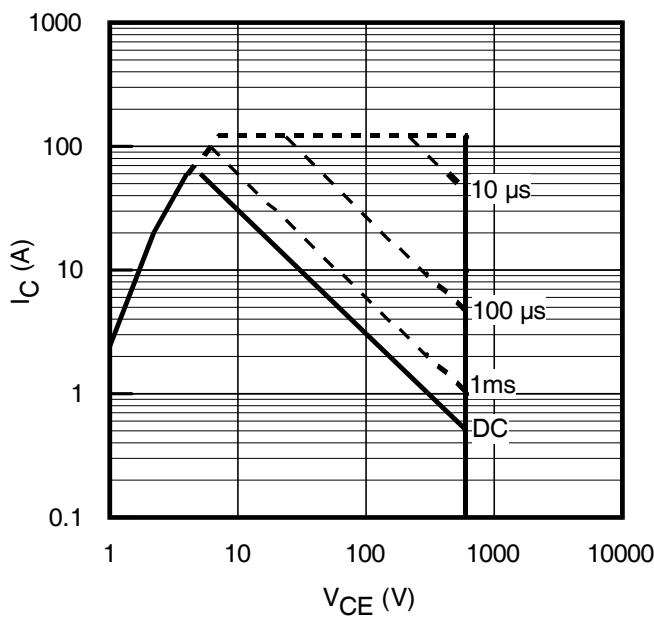


Fig. 3 - Forward SOA
 $T_C = 25^\circ\text{C}$, $T_J \leq 150^\circ\text{C}$

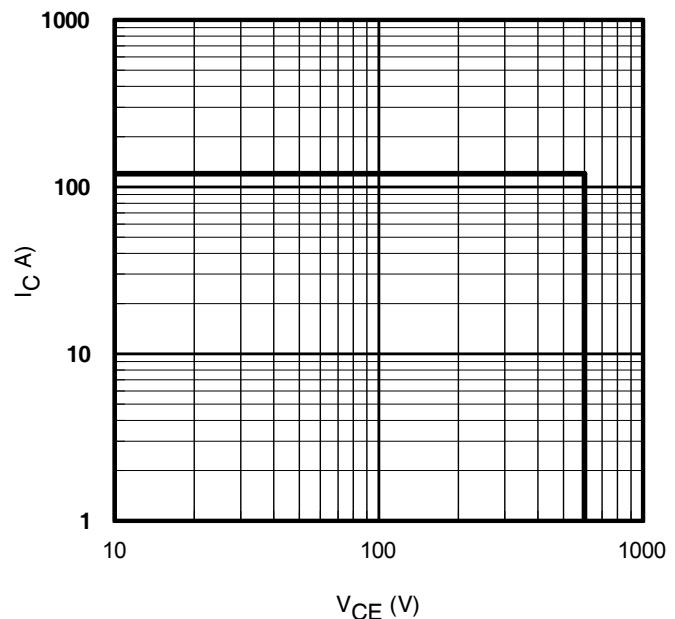


Fig. 4 - Reverse Bias SOA
 $T_J = 150^\circ\text{C}$; $V_{GE} = 15\text{V}$

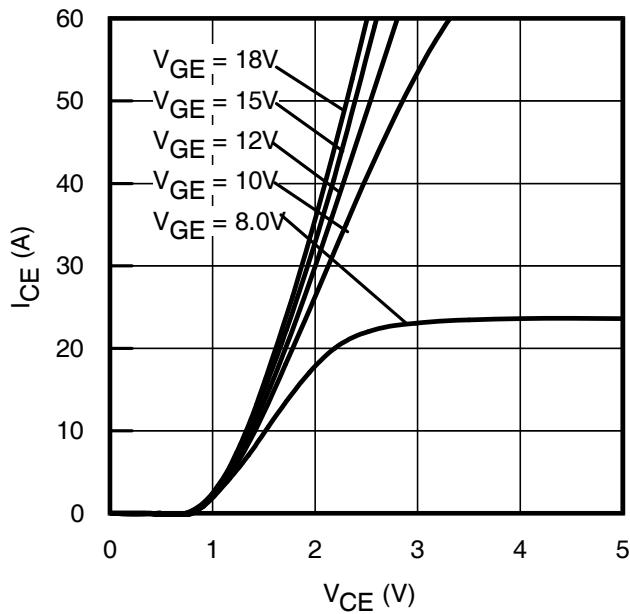


Fig. 5 - Typ. IGBT Output Characteristics
 $T_J = -40^\circ\text{C}; t_p = 80\mu\text{s}$

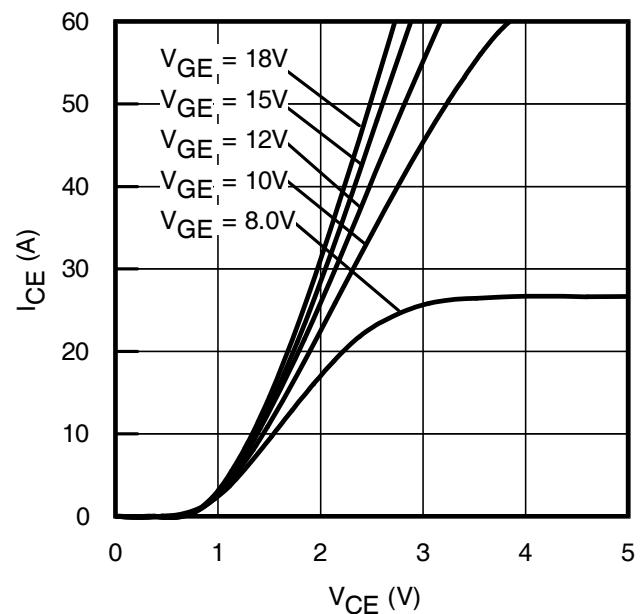


Fig. 6 - Typ. IGBT Output Characteristics
 $T_J = 25^\circ\text{C}; t_p = 80\mu\text{s}$

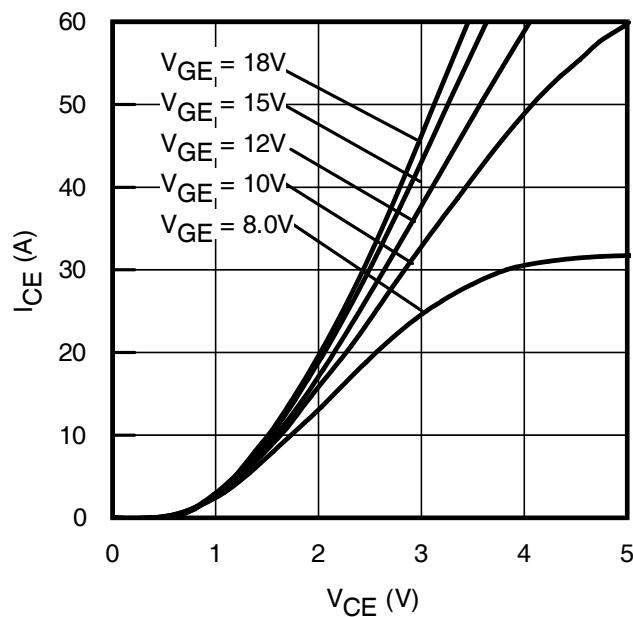


Fig. 7 - Typ. IGBT Output Characteristics
 $T_J = 150^\circ\text{C}; t_p = 80\mu\text{s}$

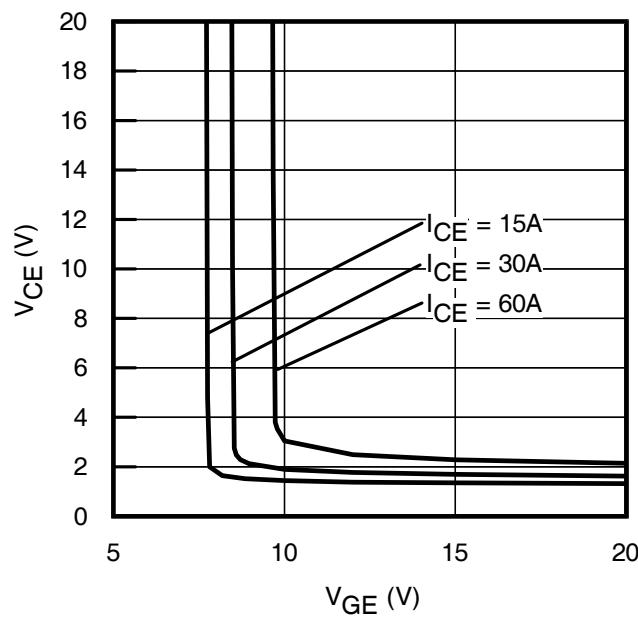


Fig. 8 - Typical V_{CE} vs. V_{GE}
 $T_J = -40^\circ\text{C}$

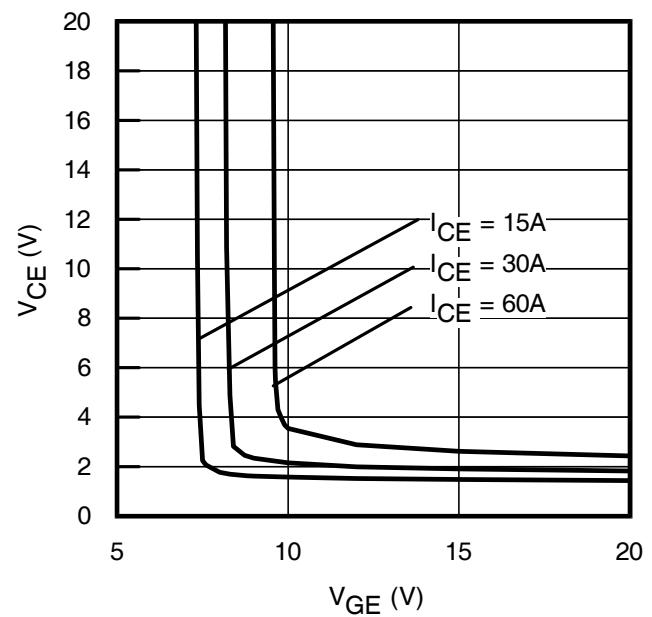


Fig. 9 - Typical V_{CE} vs. V_{GE}
 $T_J = 25^\circ\text{C}$

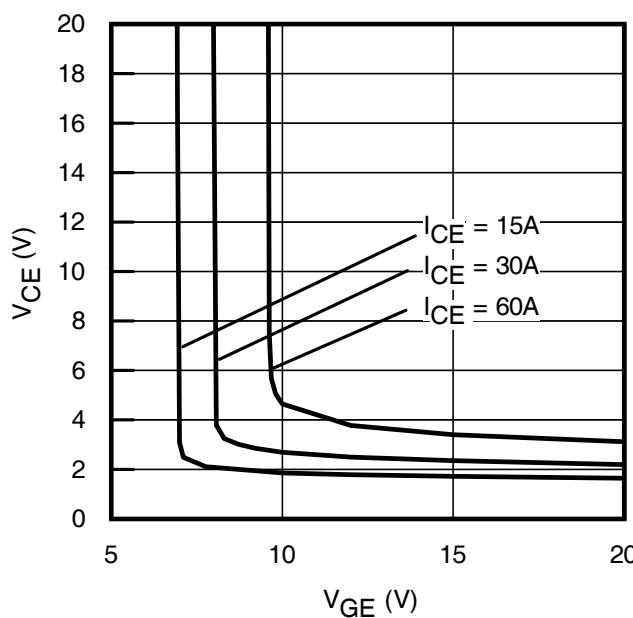


Fig. 10 - Typical V_{CE} vs. V_{GE}
 $T_J = 150^\circ\text{C}$

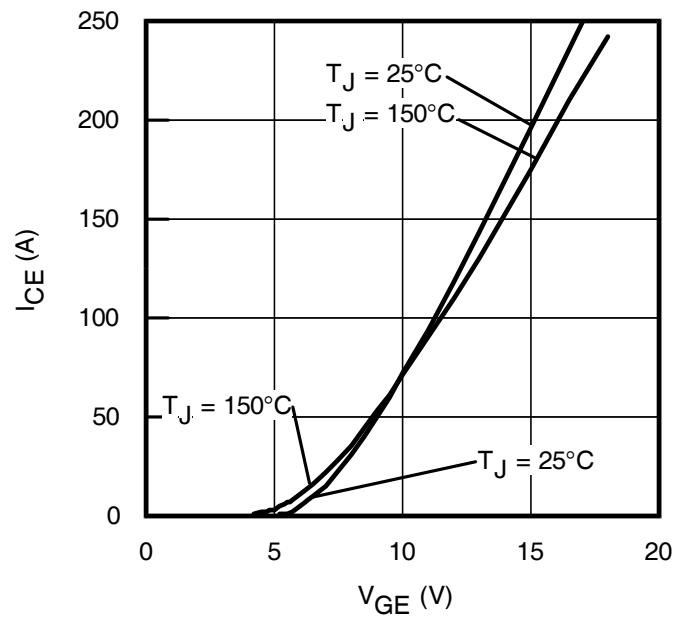
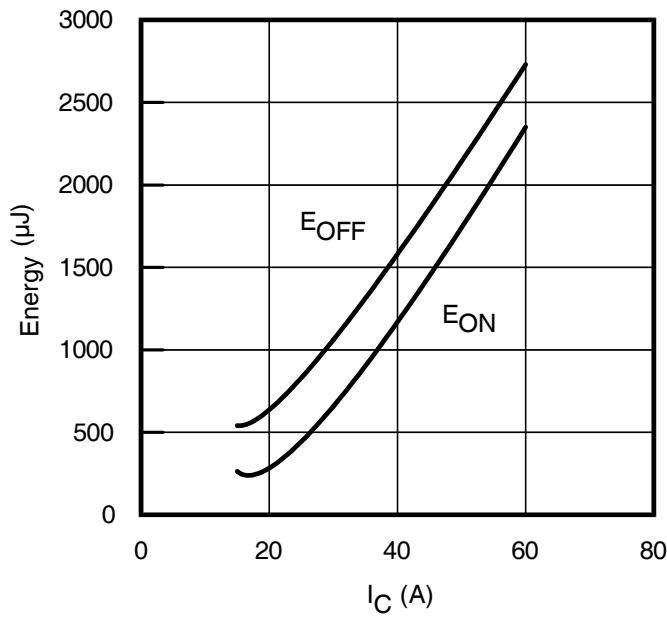
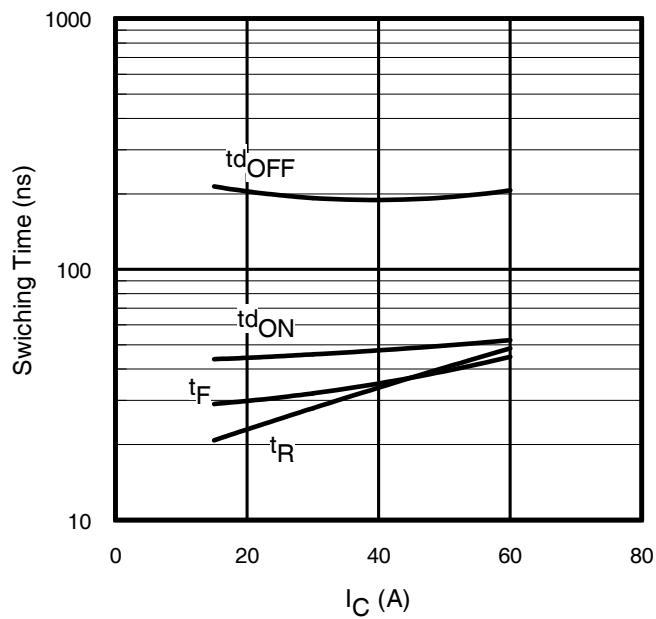


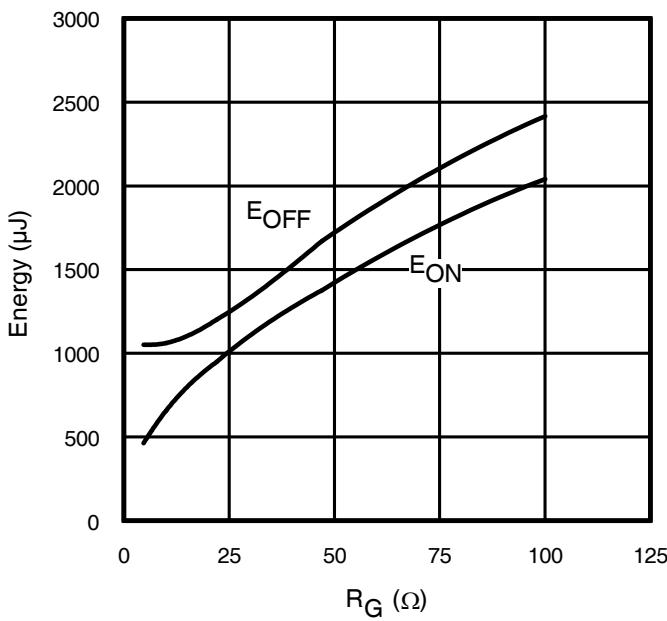
Fig. 11 - Typ. Transfer Characteristics
 $V_{CE} = 50\text{V}$; $t_p = 10\mu\text{s}$

**Fig. 12**- Typ. Energy Loss vs. I_C

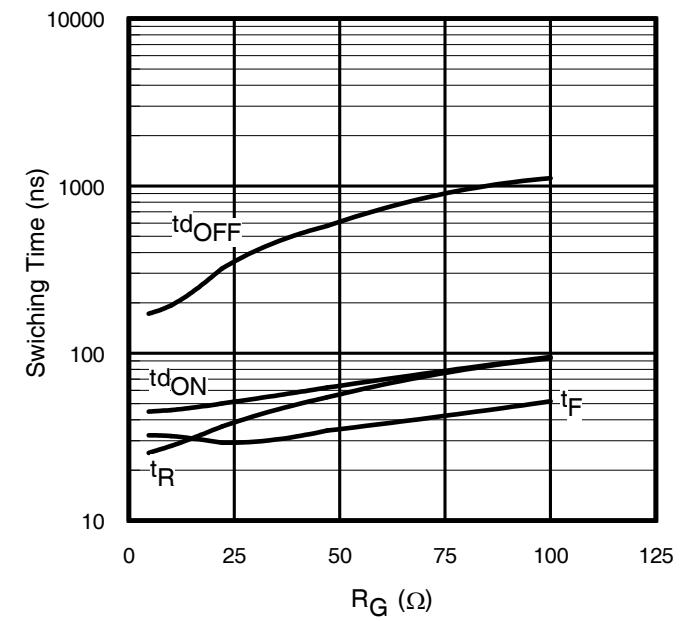
$T_J = 150^\circ C$; $L = 200\mu H$; $V_{CE} = 400V$, $R_G = 10\Omega$; $V_{GE} = 15V$

**Fig. 13** - Typ. Switching Time vs. I_C

$T_J = 150^\circ C$; $L = 200\mu H$; $V_{CE} = 400V$, $R_G = 10\Omega$; $V_{GE} = 15V$

**Fig. 14** - Typ. Energy Loss vs. R_G

$T_J = 150^\circ C$; $L = 200\mu H$; $V_{CE} = 400V$, $I_{CE} = 30A$; $V_{GE} = 15V$

**Fig. 15** - Typ. Switching Time vs. R_G

$T_J = 150^\circ C$; $L = 200\mu H$; $V_{CE} = 400V$, $I_{CE} = 30A$; $V_{GE} = 15V$

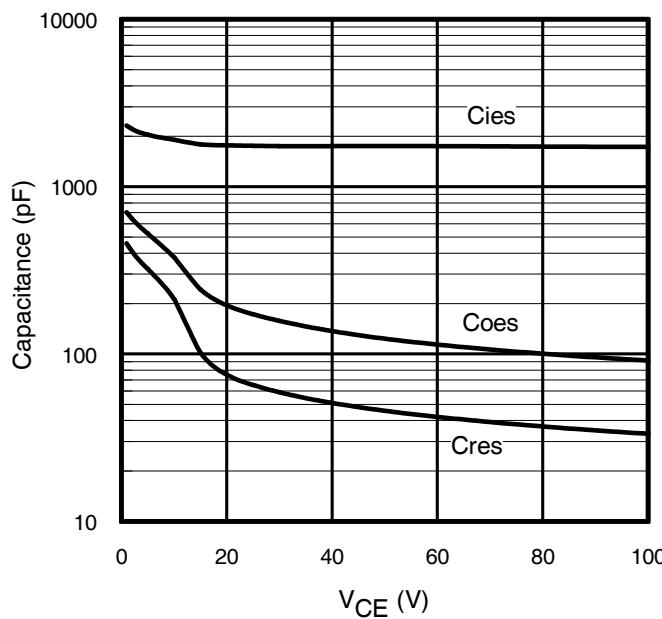


Fig. 16- Typ. Capacitance vs. V_{CE}
 $V_{GE} = 0V$; $f = 1MHz$

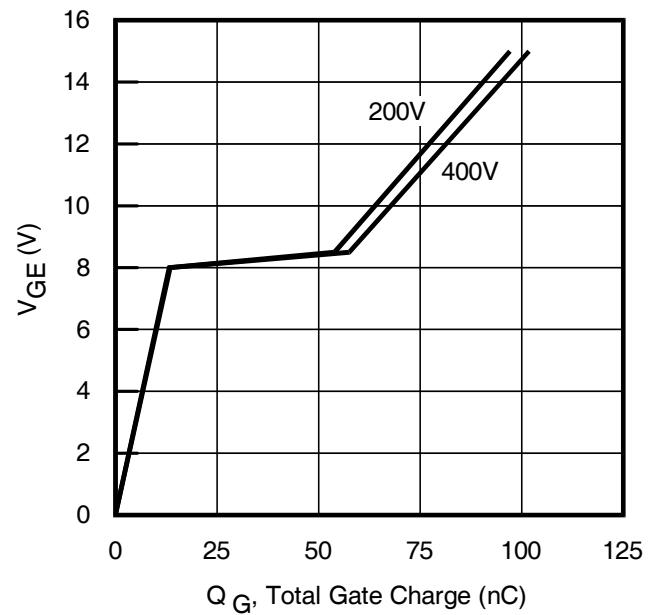


Fig. 17 - Typical Gate Charge vs. V_{GE}
 $I_{CE} = 30A$; $L = 600\mu H$

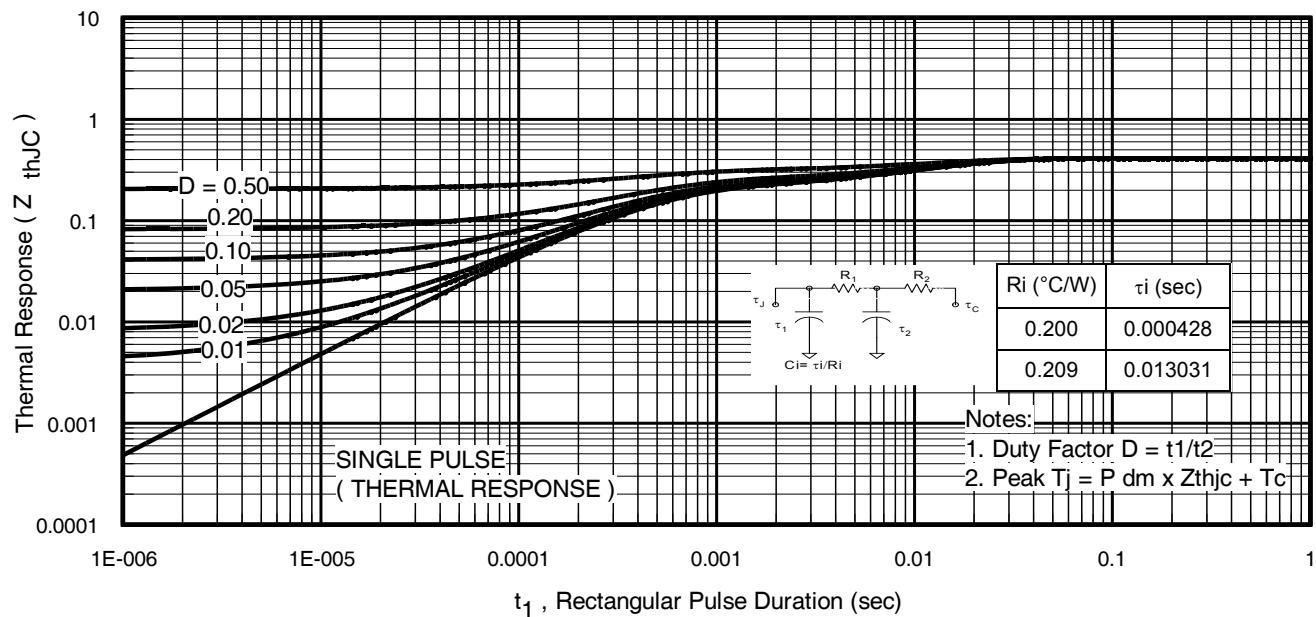


Fig 18. Maximum Transient Thermal Impedance, Junction-to-Case (IGBT)

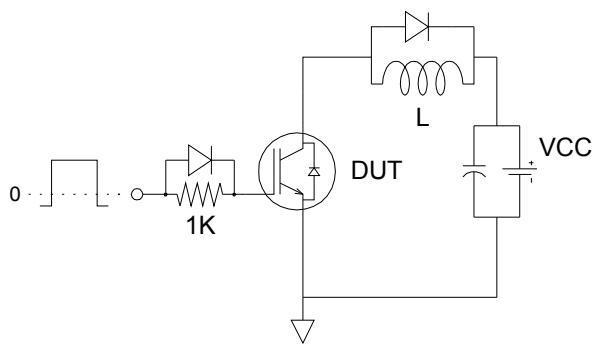


Fig.C.T.1 - Gate Charge Circuit (turn-off)

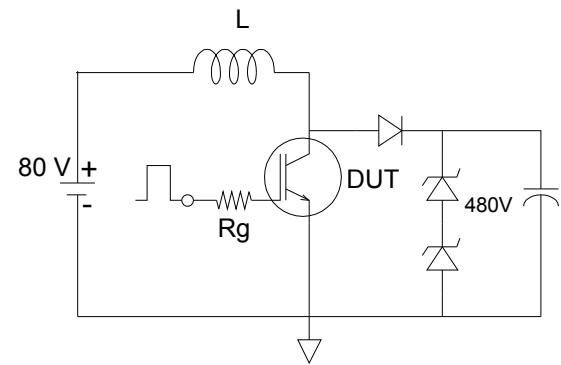


Fig.C.T.2 - RBSOA Circuit

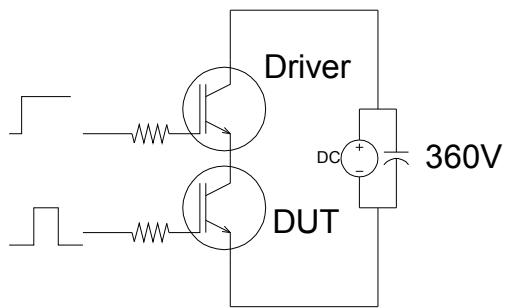


Fig.C.T.3 - S.C. SOA Circuit

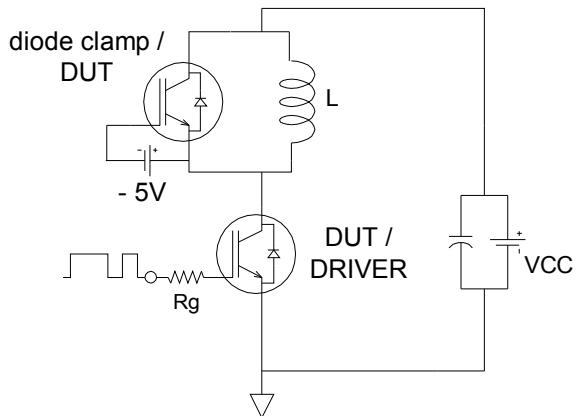


Fig.C.T.4 - Switching Loss Circuit

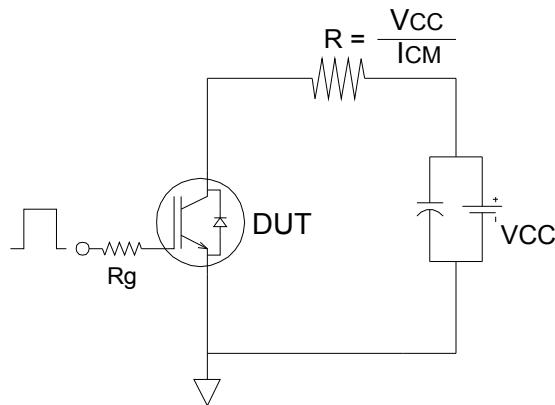


Fig.C.T.5 - Resistive Load Circuit

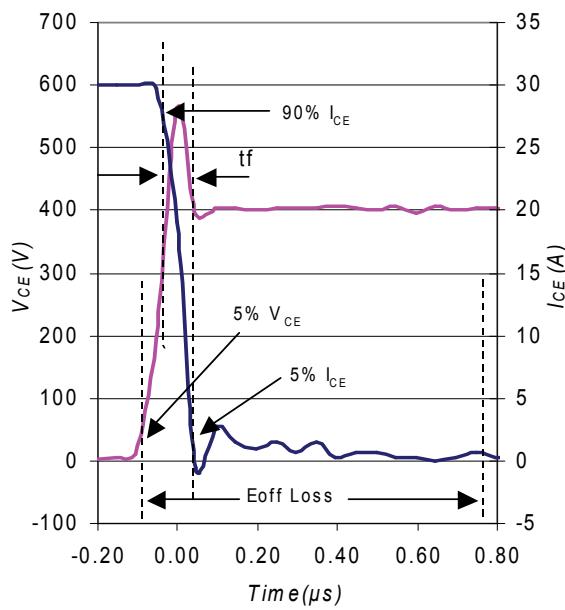


Fig. WF1 - Typ. Turn-off Loss Waveform
@ $T_J = 150^\circ\text{C}$ using Fig. CT.4

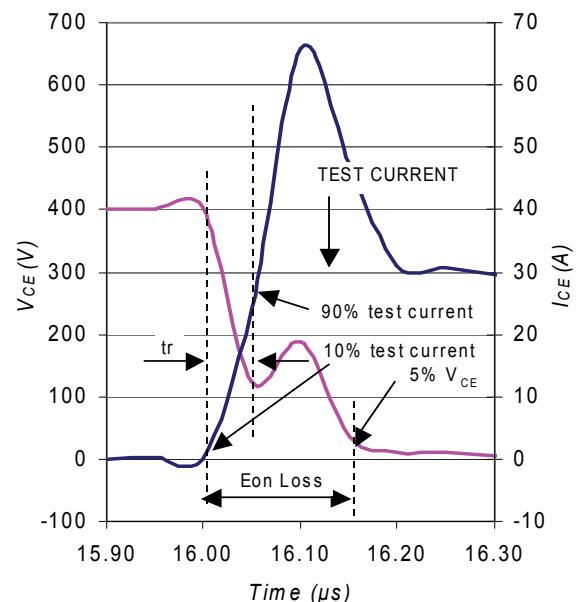


Fig. WF2 - Typ. Turn-on Loss Waveform
@ $T_J = 150^\circ\text{C}$ using Fig. CT.4

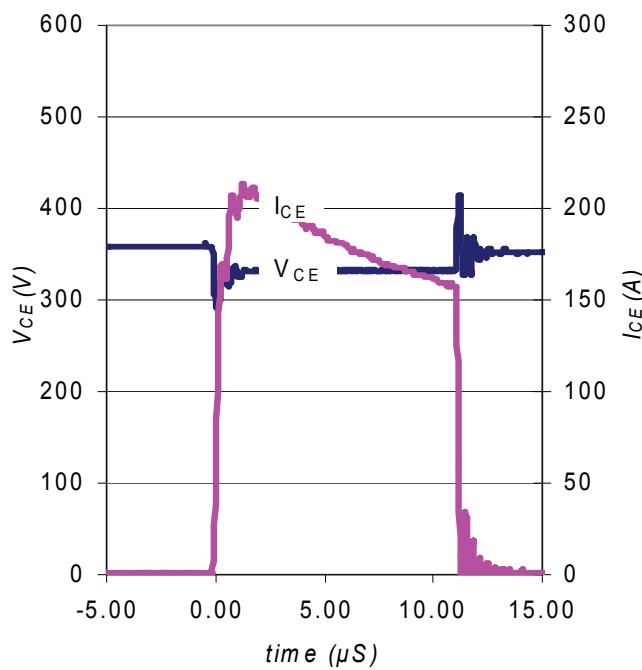
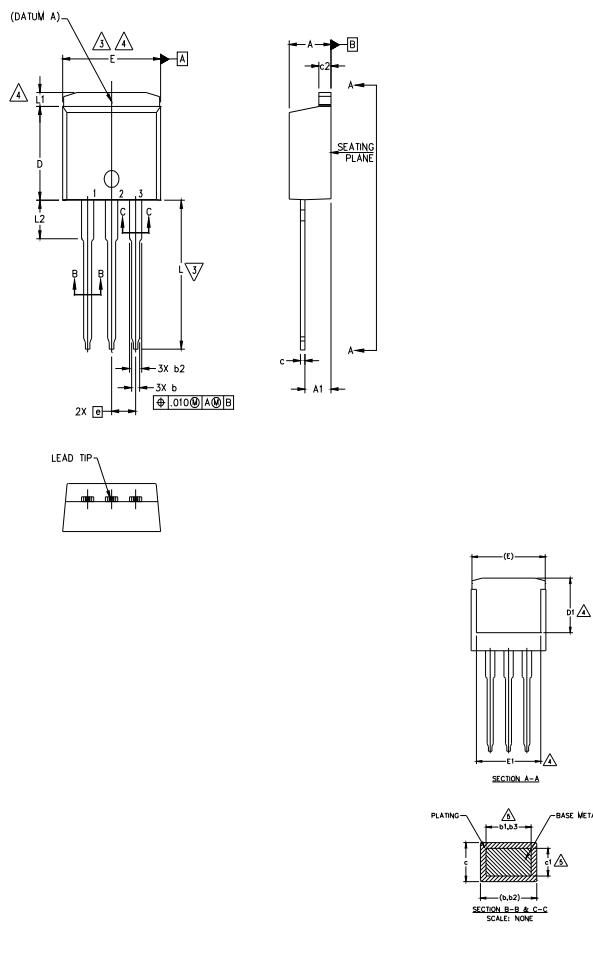


Fig. WF3 - Typ. S.C. Waveform
@ $T_J = 150^\circ\text{C}$ using Fig. CT.3

TO-262 Package Outline

(Dimensions are shown in millimeters (inches))



NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
5. DIMENSION b1 AND c1 APPLY TO BASE METAL ONLY.
6. CONTROLLING DIMENSION: INCH.
7. OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

S Y M B O L	DIMENSIONS			N O T E S
	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.06	4.83	.160	.190
A1	2.03	3.02	.080	.119
b	0.51	0.99	.020	.039
b1	0.51	0.89	.020	.035
b2	1.14	1.78	.045	.070
b3	1.14	1.73	.045	.068
c	0.38	0.74	.015	.029
c1	0.38	0.58	.015	.023
c2	1.14	1.65	.045	.065
D	8.38	9.65	.330	.380
D1	6.86	—	.270	—
E	9.65	10.67	.380	.420
E1	6.22	—	.245	—
e	2.54 BSC	—	.100 BSC	—
L	13.46	14.10	.530	.555
L1	—	1.65	—	.065
L2	3.56	3.71	.140	.146

LEAD ASSIGNMENTS

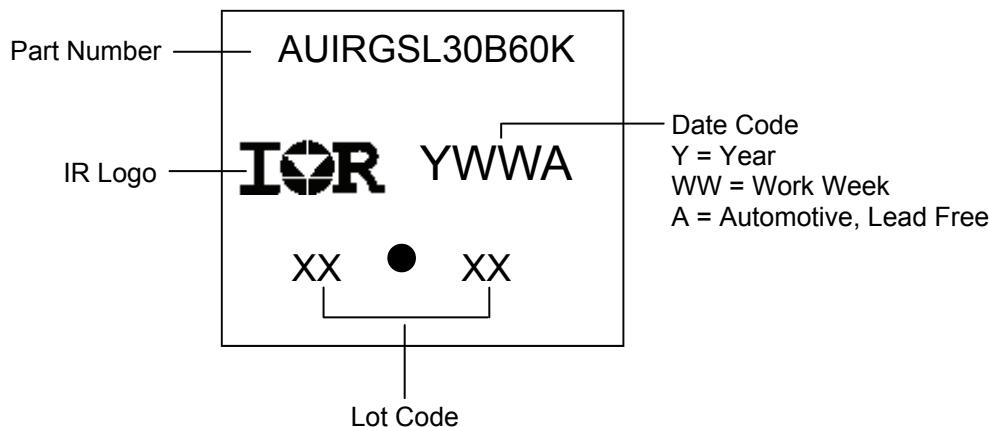
HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE
- 4.- DRAIN

IGBTs, CoPACK

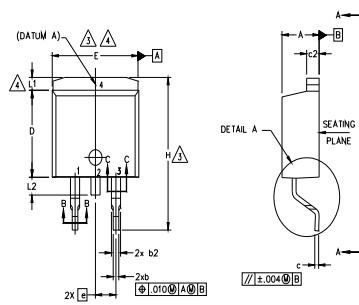
- 1.- GATE
- 2.- COLLECTOR
- 3.- Emitter
- 4.- COLLECTOR

TO-262 Part Marking Information



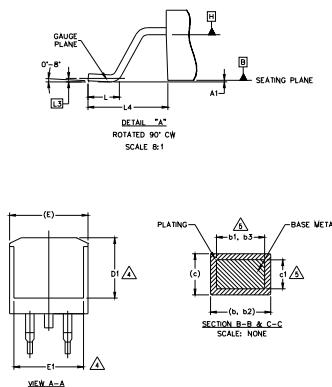
D2 Pak (TO-263AB) Package Outline

(Dimensions are shown in millimeters (inches))



NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
5. DIMENSION b1 AND c1 APPLY TO BASE METAL ONLY.
6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
7. CONTROLLING DIMENSION: INCH.
8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.



SYMBOL	DIMENSIONS				NOTES	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	4.06	4.83	.160	.190		
A1	0.00	0.254	.000	.010		
b	0.51	0.99	.020	.039		
b1	0.51	0.89	.020	.035	5	
b2	1.14	1.78	.045	.070		
b3	1.14	1.73	.045	.068	5	
c	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023	5	
c2	1.14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	—	.270	—	4	
E	9.65	10.67	.380	.420	3,4	
E1	6.22	—	.245	—	4	
e	2.54	BSC	.100	BSC		
H	14.61	15.88	.575	.625		
L	1.78	2.79	.070	.110		
L1	—	1.65	—	.066	4	
L2	1.27	1.78	—	.070		
L3	0.25	BSC	.010	BSC		
L4	4.78	5.28	.188	.208		

LEAD ASSIGNMENTS

HEXFET

- 1.- GATE
- 2, 4.- DRAIN
- 3.- SOURCE

IGBTs, CoPACK

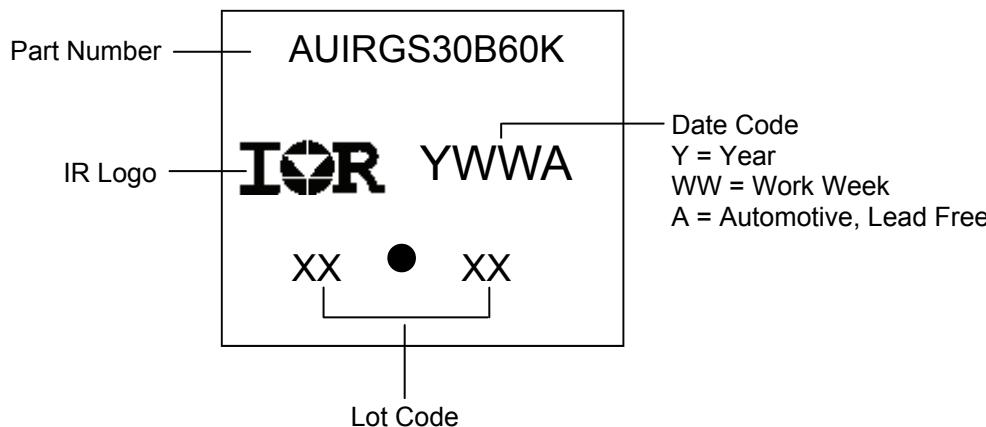
- 1.- GATE
- 2, 4.- COLLECTOR
- 3.- Emitter

DIODES

- 1.- ANODE *
- 2, 4.- CATHODE
- 3.- ANODE

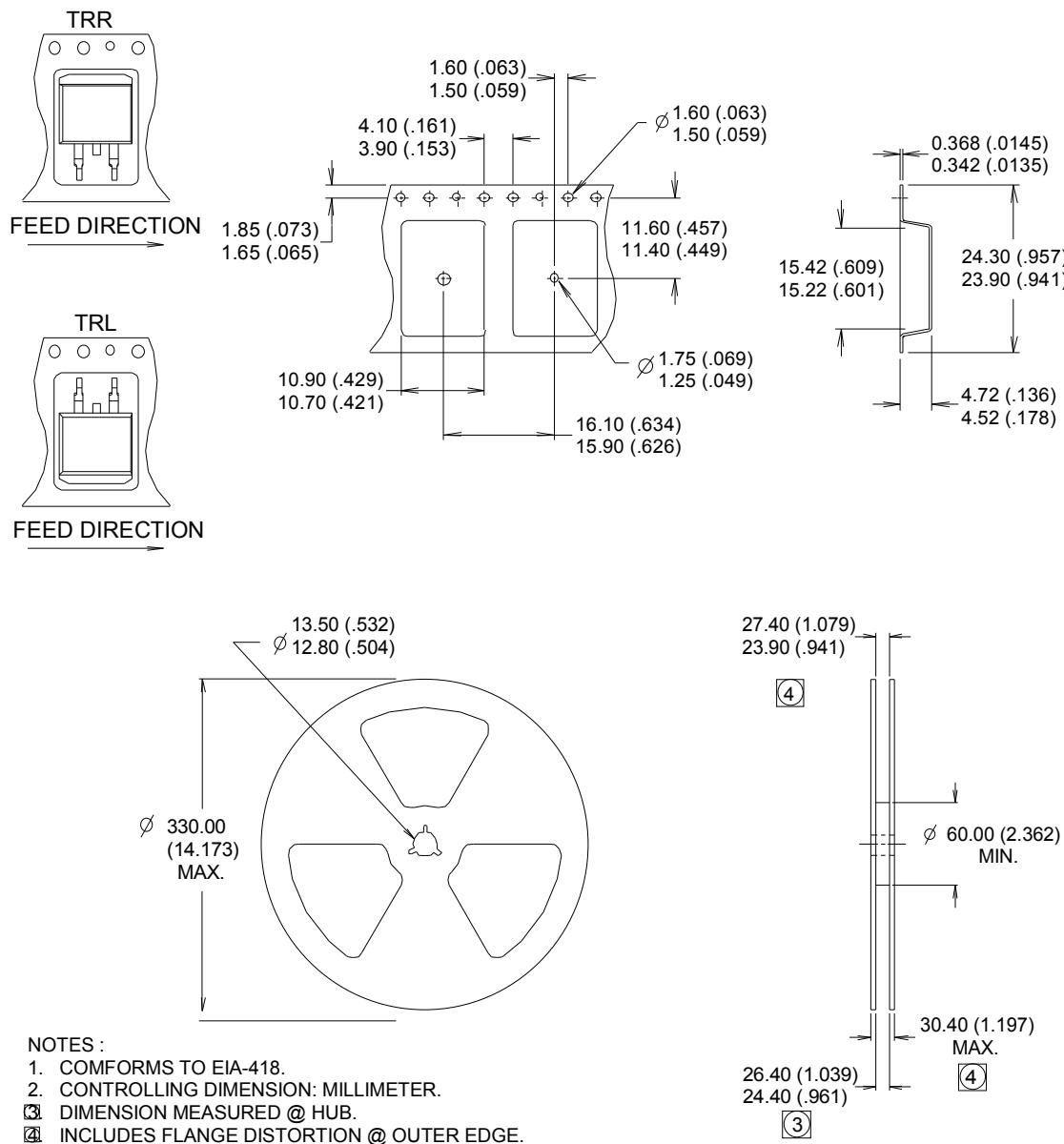
* PART DEPENDENT.

D2 Pak (TO-263AB) Part Marking Information



D2Pak Tape & Reel Information

(Dimensions are shown in millimeters (inches))



Qualification Information

		Automotive (per AEC-Q101)	
Qualification Level		This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.	
Moisture Sensitivity Level	TO-262	N/A	
	D2 PAK	MSL1	
ESD	Machine Model	Class M4(+/- 400V) [†] AEC-Q101-002	
	Human Body Model	Class H2(+/- 4000V) [†] AEC-Q101-001	
	Charged Device Model	Class C4 (+/- 1000V) [†] AEC-Q101-005	
RoHS Compliant		Yes	

† Highest passing voltage.

Revision History

Date	Comments
09/08/2017	<ul style="list-style-type: none"> • Updated datasheet with corporate template • Corrected part marking on pages 10,11.

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